TI0103-D3339, JUNE 1989-REVISED JANUARY 1990

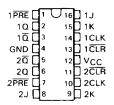
- Inputs are TTL-Voltage Compatible
- Flow-Through Architecture to Optimize PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations to Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

#### description

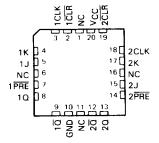
These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the Preset or Clear inputs sets or resets the outputs regardless of the levels of the other inputs. When Preset and Clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the clock pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

The 54ACT11112 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to 125°C. The 74ACT11112 is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

#### 54ACT11112 ... J PACKAGE 74ACT11112 ... D OR N PACKAGE (TOP VIEW)



#### 54ACT11112 ... FK PACKAGE (TOP VIEW)



NC-No internal connection

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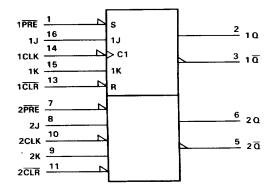
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#### **FUNCTION TABLE**

	INF	OUT	PUTS			
PRE	CLR	CLK	J	K	Q	Q
L	Н	X	Х	Х	Н	L
Н	L	×	X	X	L	Н
L	L	×	X	X	Нţ	Ht
н	н	1	L	L	$Q_0$	$\overline{Q}_0$
н	Н	1	Н	L	н	L
Н	Н	1	L	Н	L	Н
Н	н	1	Н	Н	TOGGLE	
н	Н	н	X	X	Q <sub>0</sub>	$\overline{Q}_0$

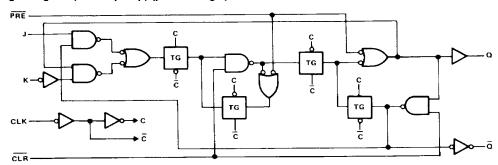
<sup>†</sup> This configuration is nonstable; that is, it will not persist when either Preset or Clear returns to the inactive (high) level.

### logic symbol‡



 $<sup>\</sup>ddagger$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, and N packages.

### logic diagram (each flip-flop) (positive logic)





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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, VCC			-0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	-0.5	V to '	V <sub>CC</sub> + 0.5 V
Output voltage range, VO (see Note 1)	-0.5	V to '	VCC + 0.5 V
Input clamp current, I <sub>IK</sub> ( $V_I < 0$ or $V_I > V_{CC}$ )			±20 mA
Output clamp current, IOK (VO < 0 or VO > VCC)			±50 mA
Continuous output current, IO (VO = 0 to VCC)			$$ $\pm 50$ mA
Continuous current through VCC or GND pins			. ±100 mA
Storage temperature range		6	55°C to 150°C

<sup>&</sup>lt;sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		54ACT1	54ACT11112		74ACT11112	
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	٧
VIH	High-level input voltage	2	Ž.	2		V
VIL	Low-level input voltage		0.8	*	0.8	V
Vį	Input voltage	0 .7	Vcc	0	Vcc	٧
Vo	Output voltage	0 %,	Vcc	0	Vcc	٧
ЮН	High-level output current	\$1.	24		- 24	mA
lOL	Low-level output current		24		24	mA
Δt/Δν	Input transition rise or fall	0	10	0	10	ns/V
TA	Operating free-air temperature	55	125	40	85	°C



NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

			TA	( = 25°C	C	54ACT11112		74ACT11112		115117	
PARAMETER	TEST CONDITIONS	TER TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		4.5 V	4.4			4.4		4.4			
	$I_{OH} = -50 \mu A$	5.5 V	5.4			5.4		5.4			
	I <sub>OH</sub> = -24 mA	4.5 V	3.94			3.7		3.8		٧	
∨он		5.5 V	4.94			4.7		4.8		٧	
	IOH = -50 mA†	5.5 V				3.85					
	$I_{OH} = -75  \text{mA}^{\dagger}$	5.5 V						3.85			
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V	
		5.5 V			0.1		0.1	-	0.1		
	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44		
VOL		5.5 V			0.36		0.5		0.44		
	IOL = 50 mA†	5.5 V					1.65				
	IOL = 75 mA <sup>†</sup>	5.5 V							1.65		
1	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μΑ	
lcc	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	5.5 V	1		4		80		40	μΑ	
ΔICC <sup>‡</sup>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			0.9		1		1	mA	
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V	1	3.5						pF	

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# timing requirements over recommended operating free-air temperature range, $V_{CC}=5$ V $\pm0.5$ V (unless otherwise noted) (see Figure 1)

				TA = 25°C		11112	74ACT11112			
PARAMETER			MIN	MAX	MAX MIN	N MAX	MIN	MAX 125	UNIT	
f <sub>clock</sub> Clock frequency			125		125	MHz				
t <sub>w</sub> Pulse duration	PRE or CLR low	4		4		4				
	Pulse duration	CLK low or high	4		4		4		ns	
		Data high or low	3.5		3.5		4.5			
t <sub>SU</sub> Setup time, data before CLK ↓		PRE or CLR inactive	2		2		2		ns	
th	Hold time, data after CLK ↓	1	1.5		1.5		1.5		ns	

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas instruments reserves the right to change or discontinue these products without notice.



<sup>‡</sup> This parameter is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to VCC.

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## switching characteristics over recommended operating free-air temperature range, $V_{CC}=5~V~\pm~0.5~V$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO	T/	TA = 25°C		54ACT11112		74ACT11112		
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
fmax			125			125	-0	125		MHz
tPLH	PRE or CLR	Q or Q	1.5	3.6	6.3	1.5	7;1	1.5	6.8	ns
tPHL			1.5	4.6	7.4	1,5	8.4	1.5	8	
tPLH .	CLK	LK Q or Q	1.5	4.2	7	1.5	8	1.5	7.7	
tPHL			1.5	4.7	7.4	1.5	8.9	1.5	8.4	ns

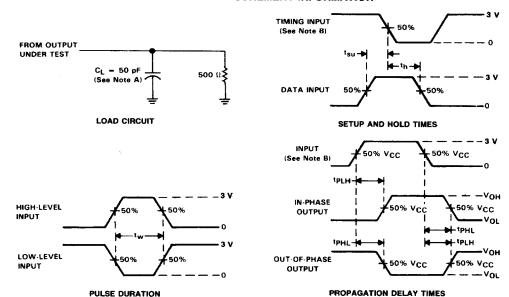
	TENNES OF THE PERSON OF THE PE			
Cpd	Power dissipation capacitance per flip-flop	$C_L = 50  pF, f = 1  f$	MHz, T <sub>A</sub> = 25°C 39	pF

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### PARAMETER MEASUREMENT INFORMATION



NOTES: A. CL includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z<sub>O</sub> = 50 Ω, t<sub>f</sub> = 3 ns, t<sub>f</sub> = 3 ns. For testing f<sub>max</sub> and pulse duration: t<sub>f</sub> = 1 to 3 ns, t<sub>f</sub> = 1 to 3 ns.
- C. The outputs are measured one at a time with one input transition per measurement.

FIGURE 1. LOAD CIRCUIT AND VOLTAGE WAVEFORMS

